

## UNITED STATES PATENT AND TRADEMARK OFFICE

DATE MAILED: 10/31/2005

UNITED STATES DEPARTMENT OF COMMERCE United States Patent and Trademark Office Address: COMMISSIONER FOR PATENTS P.O. Box 1450 Alexandria, Virginia 22313-1450 www.uspto.gov

APPLICATION NO.	FILING DATE	FIRST NAMED INVENTOR	ATTORNEY DOCKET NO.	CONFIRMATION NO	
10/715,119	11/18/2003	Kiyohito Mukai	L8462.03118	2755	
24257 7590 10/31/2005			EXAMINER		
STEVENS DAVIS MILLER & MOSHER, LLP			DOAN, N	DOAN, NGHIA M	
1615 L STR SUITE 850	EET, NW		ART UNIT	PAPER NUMBER	
·	ON, DC 20036		2825		

Please find below and/or attached an Office communication concerning this application or proceeding.

		Application No.	Applicant(s)				
Office Action Summary		10/715,119	MUKAI ET AL.				
		Examiner	Art Unit				
		Nghia M. Doan	2825				
The MAILING DATE of this communication appears on the cover sheet with the correspondence address							
Period for Reply							
WHIC - Exter after - If NC - Failu Any	ORTENED STATUTORY PERIOD FOR REP CHEVER IS LONGER, FROM THE MAILING Insions of time may be available under the provisions of 37 CFR 1 SIX (6) MONTHS from the mailing date of this communication. Operiod for reply is specified above, the maximum statutory period re to reply within the set or extended period for reply will, by staturely received by the Office later than three months after the mailed patent term adjustment. See 37 CFR 1.704(b).	DATE OF THIS COMMUNICATION .136(a). In no event, however, may a reply be timed will apply and will expire SIX (6) MONTHS from the cause the application to become ABANDONE	N. nely filed the mailing date of this communication. D (35 U.S.C. § 133).				
Status	·						
1) 又	Responsive to communication(s) filed on 18	November 2003.					
, —	This action is <b>FINAL</b> . 2b)⊠ This action is non-final.						
3)	Since this application is in condition for allowance except for formal matters, prosecution as to the merits is						
closed in accordance with the practice under Ex parte Quayle, 1935 C.D. 11, 453 O.G. 213.							
Disposit	ion of Claims						
4)⊠	Claim(s) 1-17 is/are pending in the application	n.					
	4a) Of the above claim(s) is/are withdrawn from consideration.						
5)	Claim(s) is/are allowed.						
•	6) Claim(s) is/are rejected.						
	Claim(s) is/are objected to.	- election requirement					
8)⊠	Claim(s) <u>1-17</u> are subject to restriction and/o	r election requirement.					
Applicat	ion Papers		,				
9)[	The specification is objected to by the Examin	ner.					
10)☐ The drawing(s) filed on is/are: a)☐ accepted or b)☐ objected to by the Examiner.							
Applicant may not request that any objection to the drawing(s) be held in abeyance. See 37 CFR 1.85(a).							
Replacement drawing sheet(s) including the correction is required if the drawing(s) is objected to. See 37 CFR 1.121(d).  11) The oath or declaration is objected to by the Examiner. Note the attached Office Action or form PTO-152.							
11)	The oath or declaration is objected to by the i	Examiner, Note the attached Office	; Action of form FTO-132.				
Priority (	under 35 U.S.C. § 119						
12) Acknowledgment is made of a claim for foreign priority under 35 U.S.C. § 119(a)-(d) or (f). a) All b) Some * c) None of:							
1. Certified copies of the priority documents have been received.							
2. Certified copies of the priority documents have been received in Application No							
3. Copies of the certified copies of the priority documents have been received in this National Stage							
application from the International Bureau (PCT Rule 17.2(a)).							
* See the attached detailed Office action for a list of the certified copies not received.							
Attachment(s)  1) Notice of References Cited (PTO-892)  4) Interview Summary (PTO-413)							
2) Notice of Draftsperson's Patent Drawing Review (PTO-948) Paper No(s)/Mail Date							
3) Information Disclosure Statement(s) (PTO-1449 or PTO/SB/08)  Paper No(s)/Mail Date  5) Notice of Informal Patent Application (PTO-152)  6) Other:							

Office Action Summary

## **DETAILED ACTION**

1. Responsive to communication amended of application 10/715,119 filed on 11/18/2003. Claims 1-17 are pending. Upon further consideration, this application merits a restriction requirement.

## Election/Restrictions

- 2. Restriction to one of the following inventions is required under 35 U.S.C. 121:
  - Claims 1-2, drawn to method inspection wires layout of a semiconductor device based on relationship between wires and contact hole, classified in class 716, subclass 4.
  - II. Claims 3 and 6-8, drawn to method inspection wires layout of a semiconductor device based on the total area of the contact holes, classified in class 716, subclass 4.
  - III. Claims 4-5 and 14-15, drawn to method inspection wires layout of a semiconductor device based on number of contact holes in the wires of the same node, classified in class 716, subclass 4.
  - IV. Claims 9-10, drawn to method inspection wires layout of a semiconductor device based on the step of calculating the number of the contact hole in the wires having a constant width, classified in class 716, subclass 4.
  - V. Claims 11-13, drawn to method inspection wires layout of a semiconductor device based on the steps of dividing the entire area of the chip layout into a plurality of inspection region associated with the wires of a constant width, classified in class 716, subclass 4.

Application/Control Number: 10/715,119

Art Unit: 2825

VI. Claims 16-17, drawn to method inspection wires layout of a semiconductor device using an antenna check, classified in class 716, subclass 4.

3. Invention groups I, II, III, IV, V, and VI are related as combination and subcombination. Inventions in this relationship are distinct if it can be shown that (1) the combination as claimed does not require the particulars of the subcombination as claimed for patentability, and (2) that the subcombination has utility by itself or in other combinations (MPEP § 806.05(c)). In the instant case, the combination as claimed does not require the particulars of the subcombination as claimed because:

Group I drawn to method inspection wires layout of a semiconductor device based on relationship between wires and contact hole;

Group IV drawn to method inspection wires layout of a semiconductor device based on the step of calculating the number of the contact hole in the wires having a constant width; and

Group V drawn to method inspection wires layout of a semiconductor device based on the steps of dividing the entire area of the chip layout into a plurality of inspection region associated with the wires of a constant width.

The subcombination has separate utility such as:

Group II drawn to method inspection wires layout of a semiconductor device based on the total area of the contact holes;

Group III drawn to method inspection wires layout of a semiconductor device based on number of contact holes in the wires of the same node; and

Application/Control Number: 10/715,119

Art Unit: 2825

Group VI drawn to method inspection wires layout of a semiconductor device using an antenna check

- 4. Because these inventions are distinct for the reasons given above and the search required for Group I through VI is distinct, restriction for examination purposes as indicated is proper.
- 5. Applicant is advised that the reply to this requirement to be complete must include an election of the invention to be examined even though the requirement be traversed (37 CFR 1.143).
- 6. Applicant is reminded that upon the cancellation of claims to a non-elected invention, the inventorship must be amended in compliance with 37 CFR 1.48(b) if one or more of the currently named inventors is no longer an inventor of at least one claim remaining in the application. Any amendment of inventorship must be accompanied by a request under 37 CFR 1.48(b) and by the fee required under 37 CFR 1.17(i).

## Conclusion

Any inquiry concerning this communication or earlier communications from the examiner should be directed to Nghia M. Doan whose telephone number is 571-272-5973. The examiner can normally be reached on 8:30-5:30.

If attempts to reach the examiner by telephone are unsuccessful, the examiner's supervisor, Matthew Smith can be reached on 571-272-1907. The fax phone number for the organization where this application or proceeding is assigned is 571-273-8300.

Application/Control Number: 10/715,119

Art Unit: 2825

Information regarding the status of an application may be obtained from the Patent Application Information Retrieval (PAIR) system. Status information for published applications may be obtained from either Private PAIR or Public PAIR. Status information for unpublished applications is available through Private PAIR only. For more information about the PAIR system, see http://pair-direct.uspto.gov. Should you have questions on access to the Private PAIR system, contact the Electronic Business Center (EBC) at 866-217-9197 (toll-free).

Nghia M. Doan Patent Examiner AU 2825 NMD

A. M. Thompson
Primary Examiner
Technology Center 2800